恩智浦N-AFE模拟前端产品 在工业自动化中的应用

Sally Huang NXP FAE MAY 2023



SECURE CONNECTIONS FOR A SMARTER WORLD

PUBLIC





OVERVIEW

Smart factory and the need of a software-defined factory

New NXP analog front-end enables the software-defined factory

N-AFE enhanced diagnostics enable predictive maintenance

NXP system solutions for smart factory

THE SMART FACTORY **HIERARCHY**



Terminal Layer





Cloud Application Layer









Network Layer

Ethernet, Wireless AP, Industry Switches, Routers

Sensors, PLC, Energy Measurement, Robots













Physical Resources Layer







World population to grow **2 billion by 2050**



Smart factories needed to meet the market demands



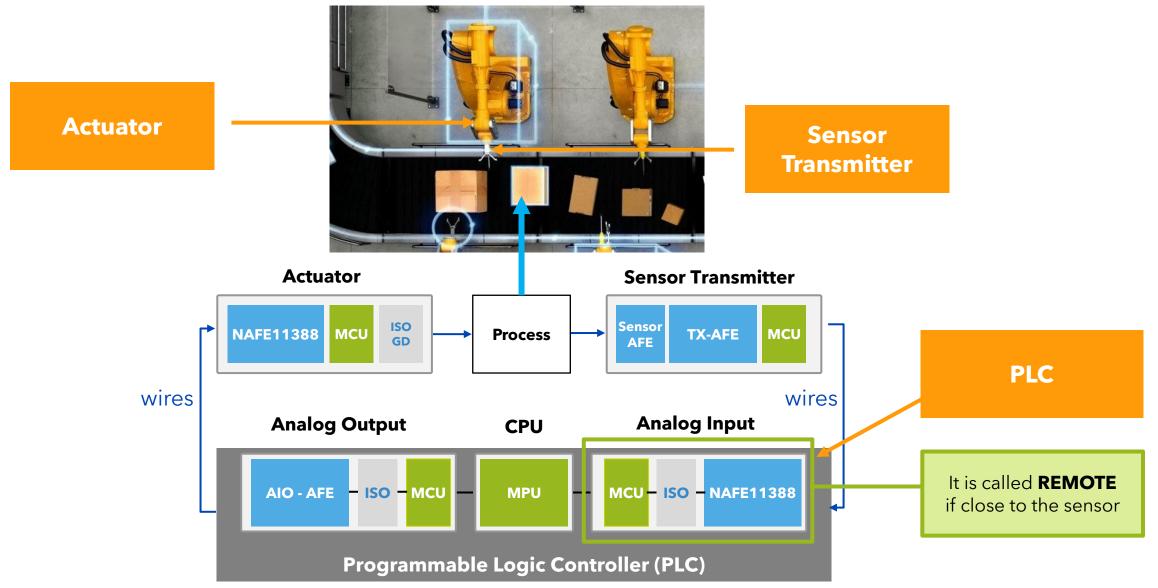
Smart factories estimated to grow US\$214.2 billion by 2026



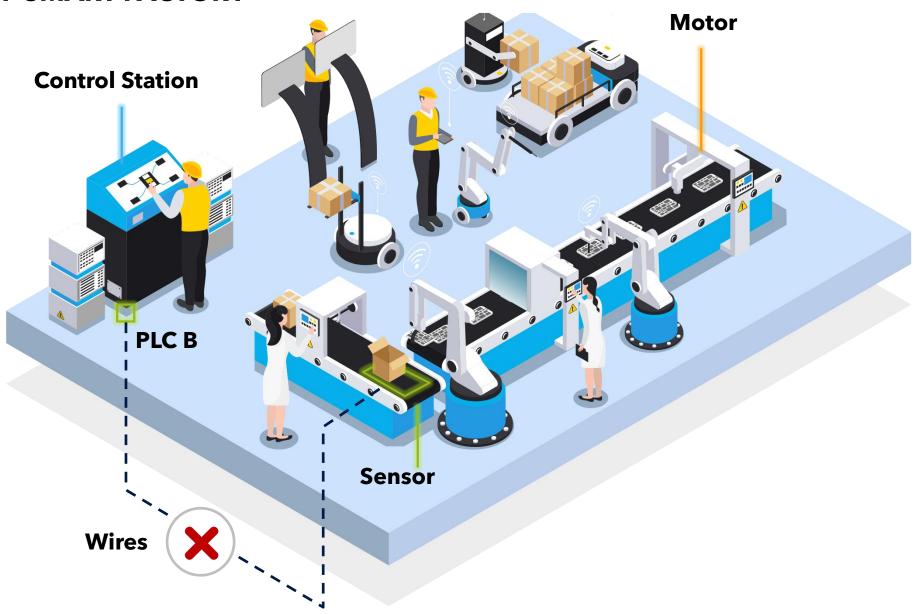
Flexible automation

offers manufacturers muchneeded resilience in an everchanging environment

AFE AND EP ENABLE THE SMART FACTORY



EXAMPLE OF SMART FACTORY







BUILD UNIQUE AFE FOR DIFFERENTIATED CUSTOMERS' SYSTEMS

Most flexible AFE architecture

Enables software-configurable universal input in a small package

High integration

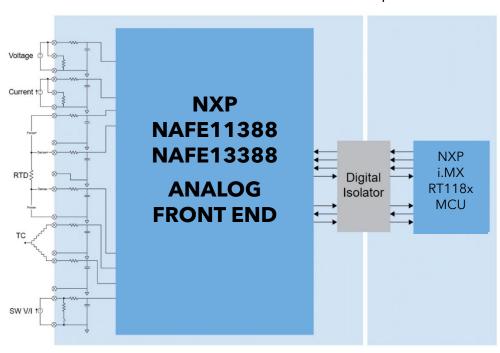
Reduces system cost

Superior accuracy, precision, and speed

Provides superior measurements performance

Unique and advanced diagnostic circuitry

Enables FuSa, anomaly detection and failure prediction



MOST FLEXIBLE AFE ARCHITECTURE



Voltage 0.15 V to 12.5V Input Range Current to **NXP** NAFE11388 RTD≷ Channels configured **ANALOG** via SPI **FRONT END** 8 kV HBM ESD IEC61000-SW V/I to 4-5 2 kV Surge protection

Analog input modules

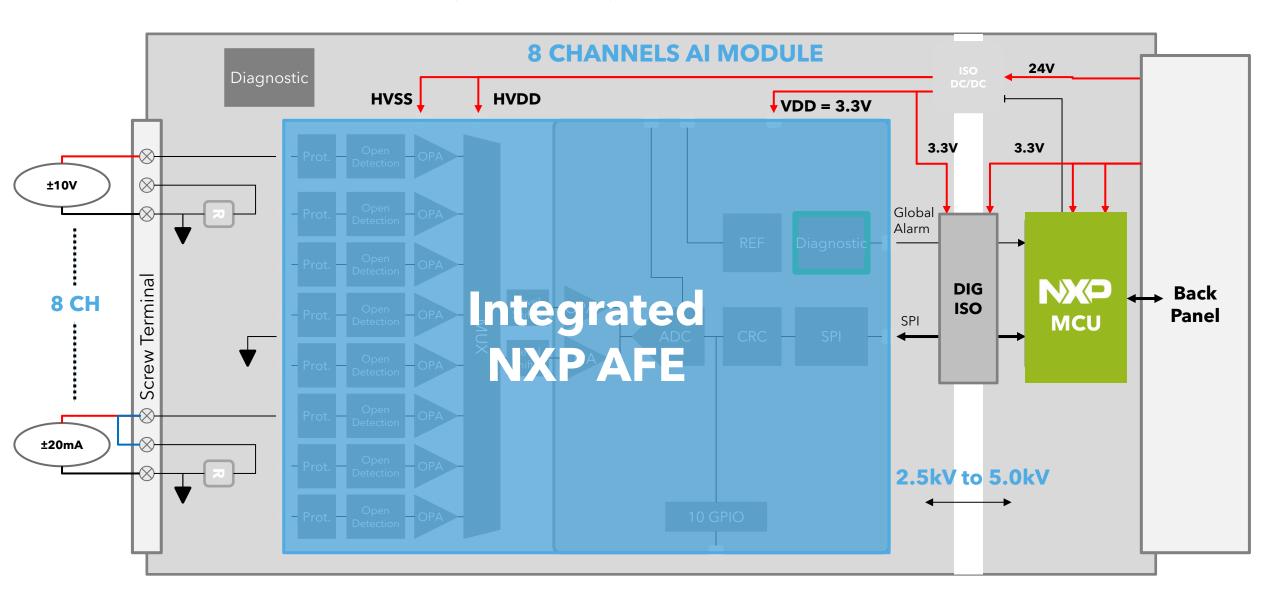
Several versions according to the sensors type

Universal input AFE

Each of the 8 channels is compatible with all sensors



AI MODULE - NXP OFFERINGS (AFE + MCU)



NAFE SERIES: WHAT'S INSIDE

REFH
AI4P
AI3P
AI2P
AI1P

AGND

Voltage/current excitation with positive and negative polarity

OVTH15 UVTH15

GAIN

CONTROL

OFFSET

SEQUENCER

CHCONF15 CHDATA15

CHCONFO CHDATAO

CALIBRATION

OFFSET15 GAIN15

ADC SETTLING MODE 10 GPIOs

Calibration registers with factory calibration option

24 bits Σ∆ ADC with digital filters

Internal voltage reference with 2 voltage sources for self calibration

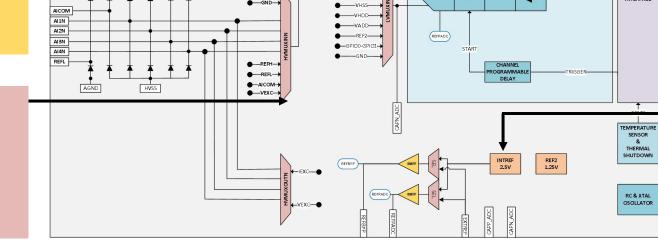
Independent digitized temperature sensor

Oscillator with low power and high speed option

8 high voltage Protected inputs and software configurable

0.2x to 16x low noise PGA

Two HV, low leakage MUX with diagnostic signals inputs



NAFE IN NUMBERS

Distinctive features

- 8 configurable HV inputs
 - Single ended or differential, with ranges up to +/-25 V
 - Configurable for voltage, current, resistance, RTD, Thermocouples
 - Over-voltage protected up to +/-36 V
- Fast Data Rate
 - NAFE11388: 7.5 SPS to 288 kSPS
 - NAFE71388: 15SPS to 576 kSPS
 - Simultaneous 50Hz/60 Hz line rejection
- Excitation Source
 - NAFE13388 / NAFE73388
- High Accuracy
 - ±0.01 % accuracy at room
 - ±0.05 % accuracy over temperature
 - ENOB:
 - NAFE11388: 17-bit at 72 kSPS / 24-bit at 30 SPS
 - NAFE71388: 17-bit at 144 kSPS / 24-bit at 50 SPS
- System Calibration
 - End-to-end calibration with integrated precise voltage sources
 - Accurate digitally calibrated products are available

- Full readout +/-3 °C accurate temperature sensor
- 0.2 % accuracy for internal oscillator
- Diagnostic system for faults detection and prediction
- CRC error detection
- 10 GPIOs
- 30 MHz SPI Interface
- 8 kV HBM ESD and IEC61000-4-5 2 kV Surge protection
- Power supply: HV: ±7 V to ±24 V, LV: 3.3 V
- Operating temperature range TA: -40 °C to 125 °C
- Package: 64 pin, 9 mm x 9 mm x 0.85 mm VQFN



Product Longevity | NXP Semiconductors

THE GOAL OF NXP'S PRODUCT LONGEVITY PROGRAM:

TO ENSURE A STABLE SUPPLY OF PRODUCTS FOR YOUR EMBEDDED DESIGNS



UNIVERSAL INPUT CONFIGURATION CHALLENGES



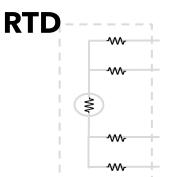
VOLTAGE 0-10 V requires high input voltage range up 12.5 V



Current 0-20 mA Requires reading currents from 0 to 20 mA with 0.2 % accuracy FS. Rsense =50 Ω Minimum voltage level 2mV 12 bits resolution is enough

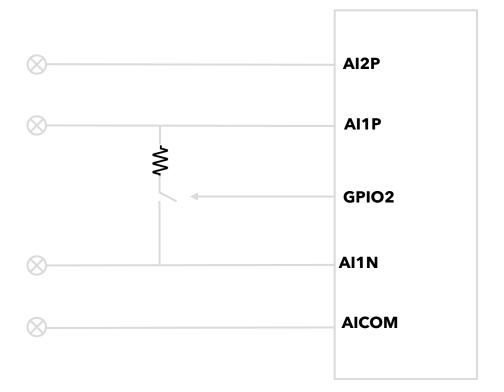


Example: K-Type -270 to 1370 °C 16 bits resolution is enough 1 °C Accuracy Needs Noise < 2µVRMS



Pt100: -200 to 800 °C 100 μ A excitation current 0.5 °C accuracy requires 11 bits but Noise < 22 μ Vrms 0.1 °C accuracy requires 13 bits but Noise < 4 μ Vrms

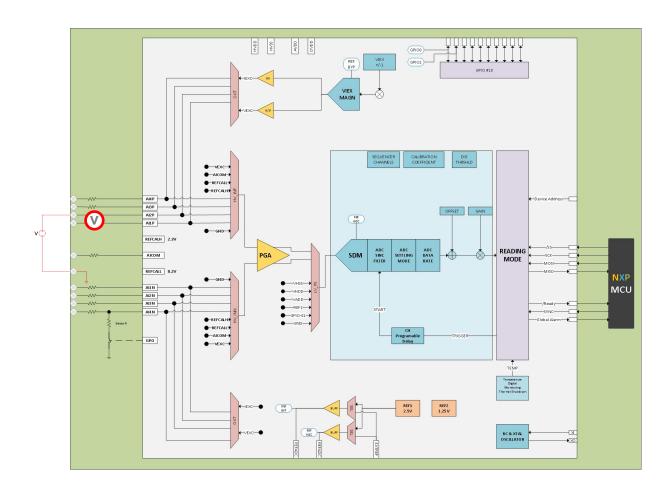
CHALLENGE: **10 V** and **2 µVRMS** Noise need to be supported by the signal chain



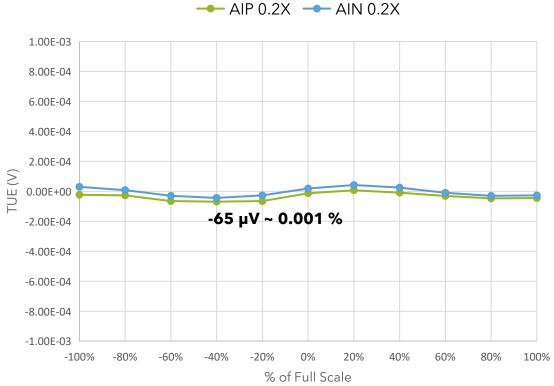
180 db Dynamic Range



TUE AND INL @ ±10 V RANGE ROOM TEMPERATURE



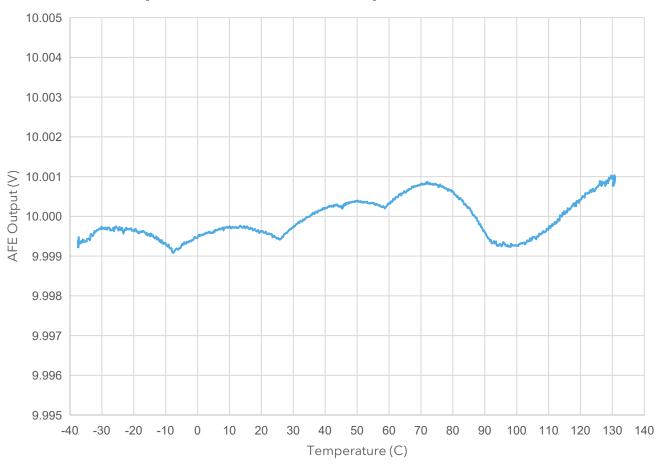
Total Unadjusted Error @ ±10 V Range





TEMPERATURE COEFFICIENT CORRECTION TCC IMPROVES GAIN DRIFT OVER TEMPERATURE

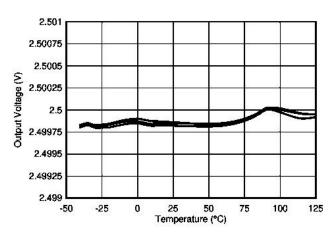
TEMPERATURE DRIFT TEST Temperature Coefficient Compensation (TCC) Enabled



End to End Accuracy

Voltage Error = +/-1 mV @ 10 V TUE = 0.01 % over 165 °C Temp Coefficient = 0.6 ppm/C Internal Voltage Reference Included

High Precision Standalone VREF



VOLTAGE AND CURRENT EXCITATION

Excitation Enables:

- resistance measurement
- biasing of RTD
- Ratiometric measurement
- built-in self-test (BIST)
- self-monitoring channel readback

Open Detection:

The excitation block includes a dedicated **65 nA** current source, for open detection on the selected Al channel. The open detection allow detect a **missing or broken** wire in the sensor connection

VIEX CHOP:

The source polarity is inverted automatically.
The Common mode voltage of the sensing circuitry is removed by averaging the difference of two ADC conversions

Voltage Excitation ±6 mV to ±12 V Current Excitation ±1 μA to ±2 mA

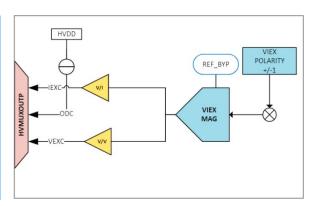


Table 15. Programmable excitation V/I source: DAC code, magnitude, and polarity

Polarity bit = 0		
DAC code	VEXC Magnitude (V)	IEXC Magnitude (A)
0	0.000	000.0E+0
1	0.006	977.0E-9
2	0.012	2.0E-6
3	0.023	3.9E-6
4	0.047	7.8E-6
5	0.094	15.6E-6
6	0.188	31.3E-6
7	0.375	62.5E-6
8	0.750	125.0E-6
9	1.500	250.0E-6
10	2.250	375.0E-6
11	3.000	500.0E-6
12	4.500	750.0E-6
13	6.000	1.0E-3
14	9.000	1.5E-3
15	12.000	2.0E-3

Polarity bit = 1		
DAC code	VEXC Magnitude (V)	IEXC Magnitude (A)
0	0.000	000.0E+0
1	-0.006	-977.0E-9
2	-0.012	-2.0E-6
3	-0.023	-3.9E-6
4	-0.047	-7.8E-6
5	-0.094	-15.6E-6
6	-0.188	-31.3E-6
7	-0.375	-62.5E-6
8	-0.750	-125.0E-6
9	-1.500	-250.0E-6
10	-2.250	-375.0E-6
11	-3.000	-500.0E-6
12	-4.500	-750.0E-6
13	-6.000	-1.0E-3
14	-9.000	-1.5E-3
15	-12.000	-2.0E-3

DIAGNOSTIC FUNCTIONS

REFH / REFL



2nd Independent Reference



Oscillator



Power Supply Check



- Drift during PCB assembly process
- Component and board aging
- Predictive maintenance

 REF_Coarse allows checking VREF drift, not detectable because same reference of the ADC

- Quartz damage
- External sync frequency missing

- Anomalies after PCB assembly
- Bad soldering of the part
- Power supply failures

Voltage / Current Excitation



Temperature Monitoring



Input Signal Check



- Open / short detection at the inputs
- Check mounting and cable degradation
- Overtemperature warning at 145 °C
- User programmable temperature threshold

- Measurement out of user selectable range
- · Input channel overload

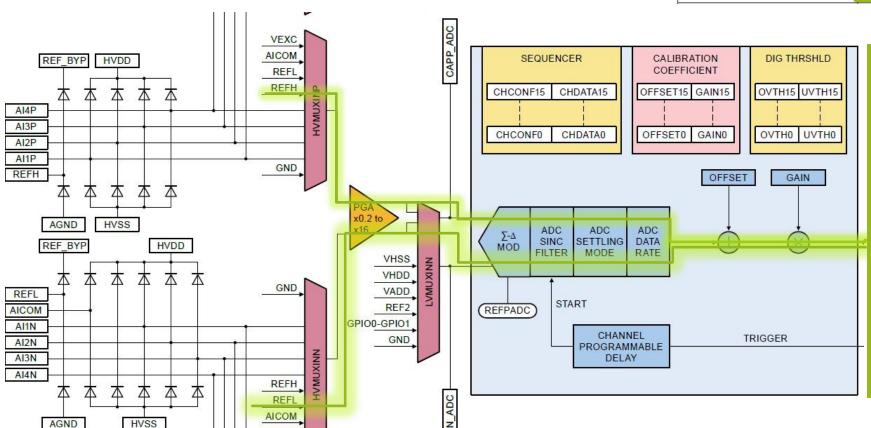
SELF CALIBRATION FOR GAIN AND OFFSET

VEXC

AGND

Table 12. Optional calibration registers

CAL REGISTER	NVM stored parameter	Nominal value
OPT_COEF0[23:0]	VREFP_ADC	2.496 V
OPT_COEF1[23:0]	REFH - GND	2.29632 V
OPT_COEF2[23:0]	REFL - GND	0.19968 V



±0.01% accuracy

Accurate REFH / REFL dual function:

- 1.Self Calibration
- 2. Diagnostic by comparing the factory cal values with the measured ones

OSCILLATOR

The internal oscillator nominal frequency is 18.432 MHz.

Auto-selection upon power on

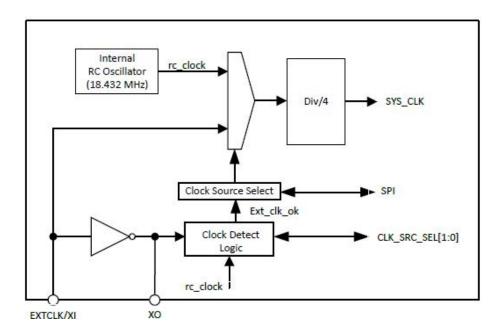


Clock Period Drift Detection

The clock running average on 128 ms (external or Crystal) is compared with the internal oscillator.

If there is a 20 % difference the Clock Alarm is issued.

NAFE Oscillator Architecture



MISWIRING PROTECTION

24 V Supply Applied to the inputs by mistake

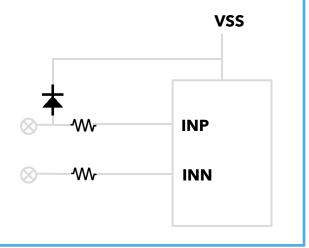
How to protect?

Option 1

Diode **before** the Resistance

Pro: no leakage on the input

Cons: no current limitation. VSS can go above the high level potentially destroying active components

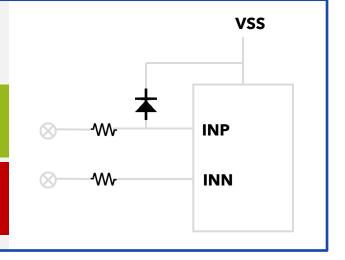


Option 2

Diode after the Resistance

Pro: current limited by the resistance

Cons: diode leakage affects the measurement

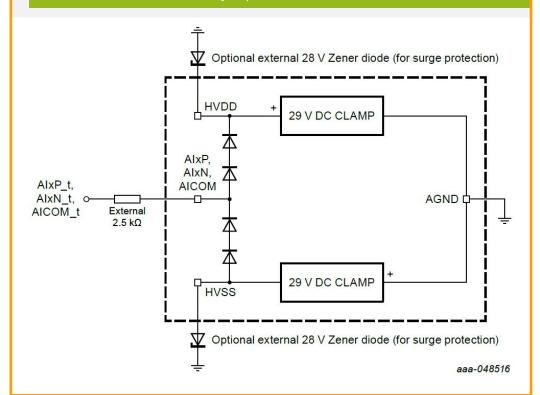


NAFE Option

Diode after the Resistance

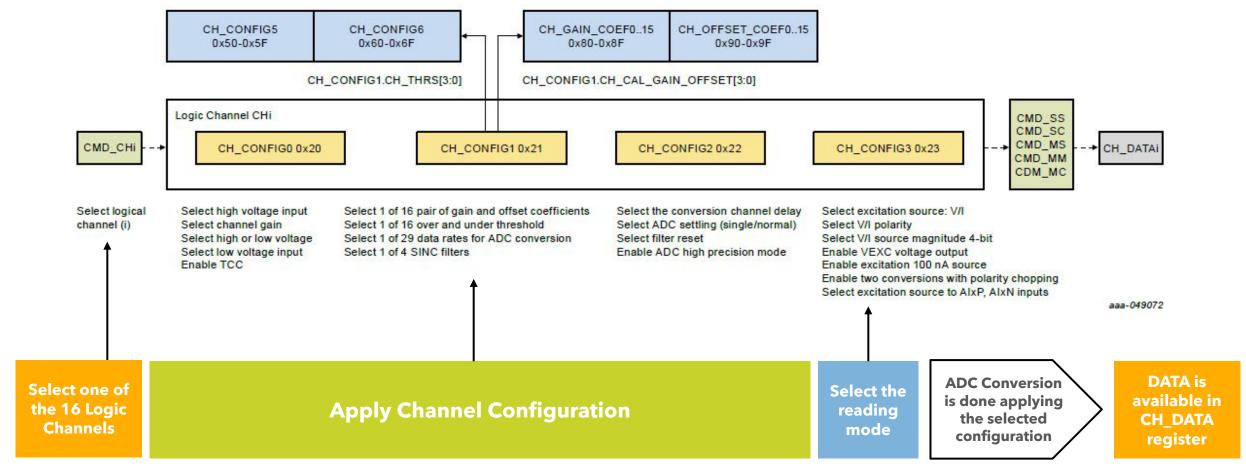
Pro: current limited by the resistance

Pro: with a **1 nA at 105 °C** leakage current of the integrated diodes, the measurement accuracy is preserved



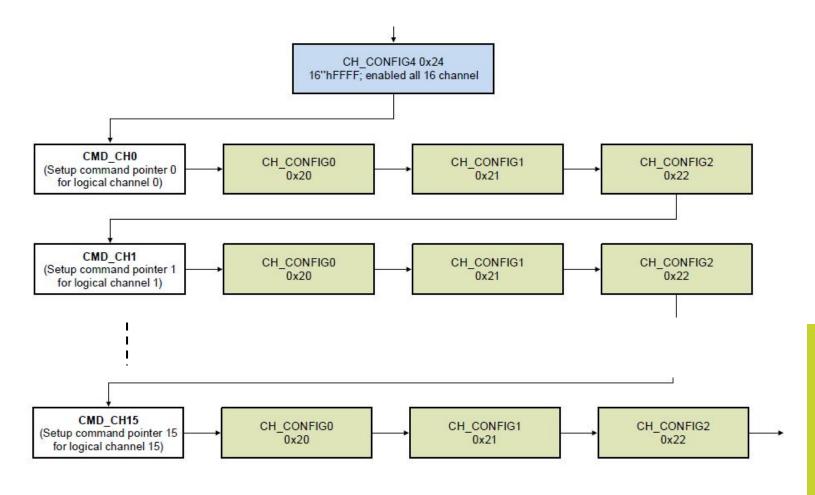
8kV HBM ESD and **IEC61000-4-5 2kV** Surge protection

16 VIRTUAL CHANNELS



Once configured at startup, the channel configuration is stored in NAFE registers. The MCU does not need to write them at each conversion

SEQUENCER



CH_CONFIG4 register allows selecting the active logic channels

The sequencer loads the corresponding configuration for the selected channel before performing the conversion

The sequencer allows saving SPI transitions reducing MCU workload and avoids SPI speed issues.

NAFE PART NUMBER VARIANTS

NAFEabcdeB40BS

a

Power / Speed

1= low power

7= high speed

b

V. Excitation

1 = no

3 = yes

C

Factory

<u>Calibration</u>

1 = no

3= yes

d

Resolution

4= 16 bit

8 = 24 bit

e

Channels

4= 4 inputs

8= 8 inputs

Released Parts

NAFE11388: Low Power - No VIEX - Cal - 24 bits - 8 ch

NAFE71388: High Speed- No VIEX - Cal - 24 bits - 8 ch

NAFE13388: Low Power - VIEX - Cal - 24 bits - 8 ch

NAFE73388: High Speed- VIEX - Cal - 24 bits - 8 ch

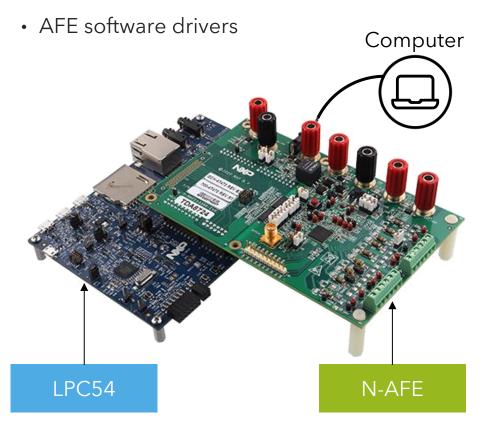


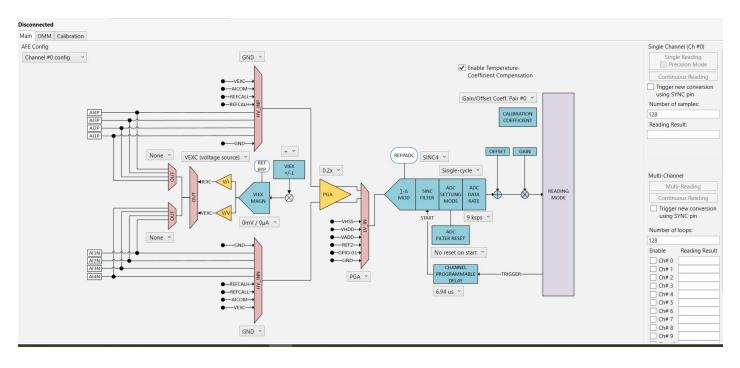
SYSTEM SOLUTIONS OVERVIEW

N-AFE SYSTEM EVALUATION KIT

KITNAFE11388-EVB

NAFE1x388 / NAFE7x388 + LPC54





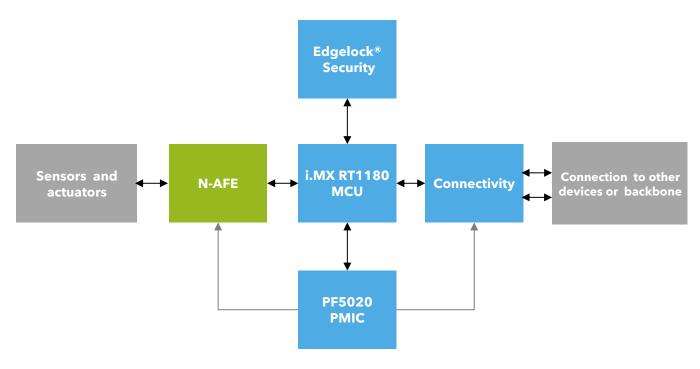
NAFE11388-EVB

(NAFE Board + USB cable + wall power adaptor)





INDUSTRIAL PLATFORM OPTIMIZED FOR THE SMART FACTORY



INDUSTRY 4.0

Factory Automation Controller

NAFE PERFORMANCES ENABLE PREDICTIVE MAINTENANCE IN MOTOR DRIVE

i.MX RT Industrial Drive Development Platform

Daughter card (ISI-QMC-DGC02)

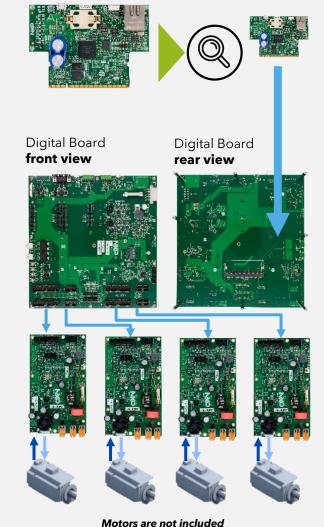
Control board, which integrates MCU chip, debugging interface and Ethernet TSN port.

Digital Board (ISI-QMC-DB02)

Expansion board for Daughter Card, integrates multiple peripherals for communication, security and display.

Power Stage Board (ISI-QMC-PSB02)

Transforms the control commands into power signals to drive servo motor (200W up to 450W)



DETECT

Sense small anomaly in presence of large signal with wide dynamic range AFE Enable easy implementation

PREDICT

Predict failure with powerful EP + Algorithms

Avoid unexpected downtime and plan maintenance

PREVENT

Reduce the anomaly and prevent failure Increase system life-time





UNIVERSAL INPUT REMOTE I/O SYSTEM SOLUTION



i.MX RT1180 Crossover MCU

- Dual core with ARM Cortex M7 at up to 800MHz and ARM Cortex M33 at up to 240MHz
- Enabling IEC 62443 system-level compliance, and IEC 60802 industrial profile support
- Enhanced Drive capability
- Secure , Compact and Low power

DETECT

PREDICT



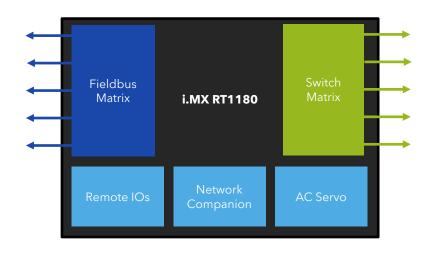
PREVENT

NAFE measures all types of sensors Provide diagnostics to the MCU

RT1180 elaborates the digitized information

Change the AFE configuration by software through SPI

Communicate to the network layer with TSN capability

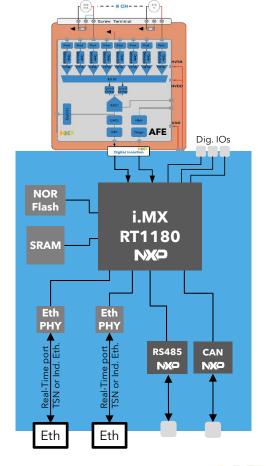


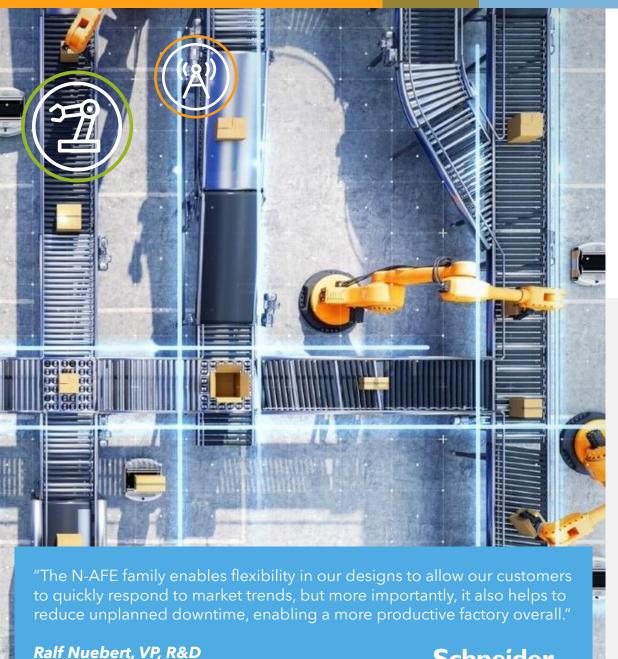




Remote I/O

System solution with **NXP's AFE**





SOFTWARE-DEFINED FACTORY

ENABLED BY N-AFE NXP ANALOG FRONT END

Most flexible analog front-end with software-configurable analog inputs



RECONFIGURABILITY

Reconfigure a smart factory and adjust settings based on shifting market needs



ACCURACY AND PRECISION

Improved **product quality** thanks to enhanced accuracy and precision



Diagnostics and anomaly detection to identify issues before they occur

PREDICTIVE MAINTENANCE



JOURNEYS BY DESIRED ENGAGEMENT

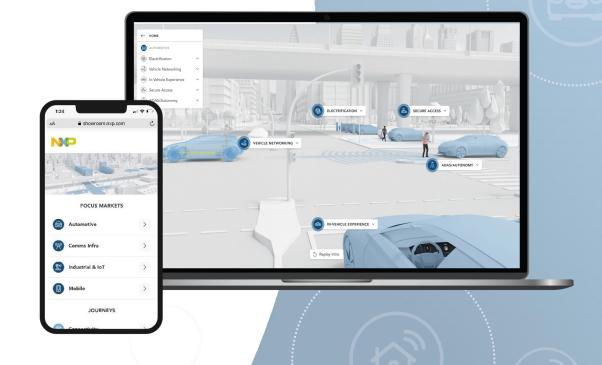
Self-guided tour Live-streaming at set times Guided tours

JOURNEYS BY DESIRED FOCUS

Low Power Innovations Advanced Analog Connectivity Edge & AI/ML Safety & Security

60+ VIRTUAL DEMOS

Focus on system solutions Set up along NXP verticals





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SECURE CONNECTIONS FOR A SMARTER WORLD



